

QUERY CONTROL FORM			RTIS USE ONLY	
Application No.	<u>10/644,926</u>	Prepared by	<u>BSH</u>	Tracking Number
Examiner-GAU	<u>Pekt-2829</u>	Date	<u>06-02-04</u>	Week Date
		No. of queries	<u>1</u>	<u>05940563</u>
				<u>04-26-2004</u>
				<u>IFW RU7</u>

JACKET

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|----------------------|------------------------|--------------------|----------------|
| a. Serial No. | f. Foreign Priority | k. Print Claim(s) | p. PTO-1449 |
| b. Applicant(s) | g. Disclaimer | l. Print Fig. | q. PTOL-85b |
| c. Continuing Data | h. Microfiche Appendix | m. Searched Column | r. Abstract |
| d. PCT | i. Title | n. PTO-270/328 | s. Sheets/Figs |
| e. Domestic Priority | j. Claims Allowed | o. PTO-892 | t. Other |

SPECIFICATION

- a. Page Missing
- b. Text Continuity
- c. Holes through Data
- d. Other Missing Text
- e. Illegible Text
- f. Duplicate Text
- g. Brief Description
- h. Sequence Listing
- i. Appendix
- j. Amendments
- k. Other

MESSAGE

Please either initial or line through citations. Copy provided for reference,

CLAIMS

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- c. Duplicate Numbers
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Thank you

initials BSH

RESPONSE

initials

Form PTO-1449 (Rev. 8-83)		U.S. Department of Commerce Patent and Trademark Office		Docket No. 740756-2406		Serial No. Not Yet Assigned
INFORMATION DISCLOSURE STATEMENT						
(Use several sheets if necessary)				Applicant: Shunpei YAMAZAKI et al.		
				Filing Date: January 15, 2002 Group: 2813		
U.S. PATENT DOCUMENTS						
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
	5,648,277	07/15/1997	Zhang et al.			
	5,643,826	07/01/1997	Ohtani et al.			
	6,124,154	09/26/2000	Miyasaka			
	5,550,070	08/27/1996	Funai et al.			
FOREIGN PATENT DOCUMENTS						
	Document Number	Date	Country	Class	Subclass	Translation Yes N
	08-078329	03/22/1996	Japan			Abstract
	07-321339	12/08/1995	Japan			Abstract
	07-130652	05/19/1995	Japan			Abstract
	07-135318	05/23/1995	Japan			Abstract
	05-109737	04/30/1993	Japan			
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)						
	R. Shimokawa and Y. Hayashi, "Characterization of High-Efficiency Cast-Si Solar Cell Wafers by MBIC Measuremant", Japanese Journal of Applied Physics, Vol. 27, No. 5, May, 1988, pp. 751-758					
Examiner	Date Considered					
*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.						